

# Device Design and Efficiency Subteam Report

## Team Members

Scott Jones	Energy Conversion Devices, Inc
Robert Collins	Penn State University
Chris Wronski	Penn State University
Eric Schiff	Syracuse University
Xunming Deng	University of Toledo
Jeff Yang/Baojie Yan	United Solar Systems Corp.

Presented at the 17<sup>th</sup> a-Si National R&D Team Meeting

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Vail Marriott Mountain Resort, Vail, Colorado

# Device Design and Efficiency subteam

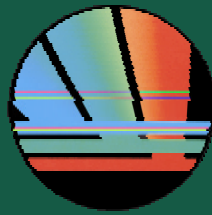
## Team priorities

### **Urgent Issues with highest priority**

- Fabricate and improve a-Si/a-SiGe/ $\mu$ c-Si triple cell
- Establish device physics related to  $\mu$ c-Si and thin film Si
- Study the dependence of  $\mu$ c-Si formation on different substrates
- Evaluate and improve the doped layer in multiple junction structure for  $\mu$ c-Si bottom cell i-layer
- Study and control the p-i and n-i interface layers for narrow bandgap cells
- Deposition of a-SiGe and  $\mu$ c-Si material at high deposition rate
- Optical designs for light enhancement
- Identify and develop consensus on approaches that have the highest possibility to lead to 15% stable solar cells.

### **Important Issues:**

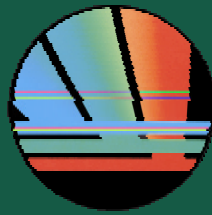
- Characterization techniques for  $\mu$ c-Si and correlation of these measurements with device performance
- Post-deposition treatment for  $\mu$ c-Si solar cells
- Understanding and improving Voc
- Deposition of  $\mu$ c-Si in large area.



## Large-area deposition using the 30 MW/year production constrains

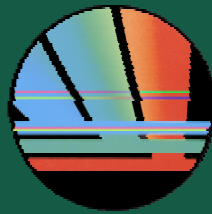
1. Modified the large-area deposition machine with new cathode design to simulate 30 MW/year production machine
2. Improved the uniformity over a larger area deposition (see the table below)
3. Started optimization of component and triple-junction cells using  $\text{SiH}_4$  instead of  $\text{Si}_2\text{H}_6$
4. Achieved an initial total-area efficiency of 10% with a-Si:H/a-SiGe:H/a-SiGe:H triple-junction structure

# UNITED SOLAR SYSTEMS CORP.



Average thickness uniformity data of individual layers for old and new cathodes, where Hi-Lo (%) = (maximum thickness – minimum thickness) / maximum thickness and CV (%) = standard deviation/average.

Layer	Cathode	Hi - Lo (11 x 11")	CV (11 x 11")
I1	Old	54%	22.5%
	New	24%	10%
I2	Old	46%	17.9%
	New	23%	8%
I3	Old	55%	21.3%
	New	23%	8.5%



**Initial total-area (0.268 cm<sup>2</sup>) performance of component and triple-junction cells made using large-area machine after installation of new cathode. The cells were deposited with SiH<sub>4</sub> over 11" × 11" deposition area.**

Sample	Structure	Substrate	Light	P <sub>max</sub> (mW/cm <sup>2</sup> )	J <sub>sc</sub> (mA/cm <sup>2</sup> )	V <sub>oc</sub> (V)	FF
9117	top	SS	AM1.5	6.36	8.55	1.004	0.741
9179	middle	SS	>530 nm	3.45	7.42	0.678	0.687
9170	bottom	Al/ZnO	>630nm	3.08	8.14	0.595	0.635
9381	triple	Al/ZnO	AM1.5	10.0	6.40	2.242	0.704

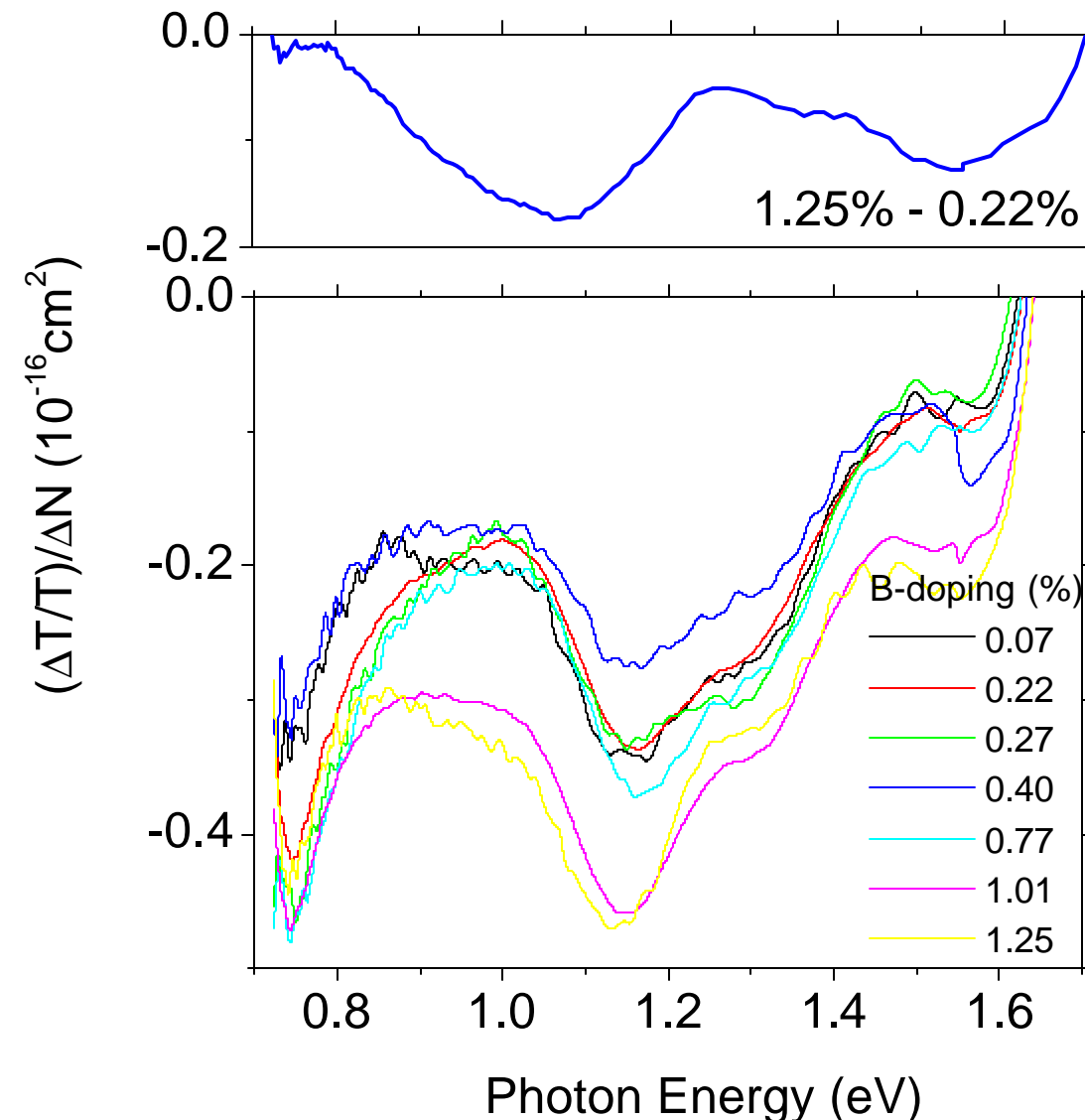
**Goal:** Efficiency > 9.0% encapsulated stable large-area cell with aperture-area of 460 cm<sup>2</sup>.

**Required cell efficiency:** In order to achieve this goal, we need an initial total-area (0.268 cm<sup>2</sup>) cell efficiency > 11.2%

# a-Si & $\mu$ c-Si Device Physics Projects: Recent Progress

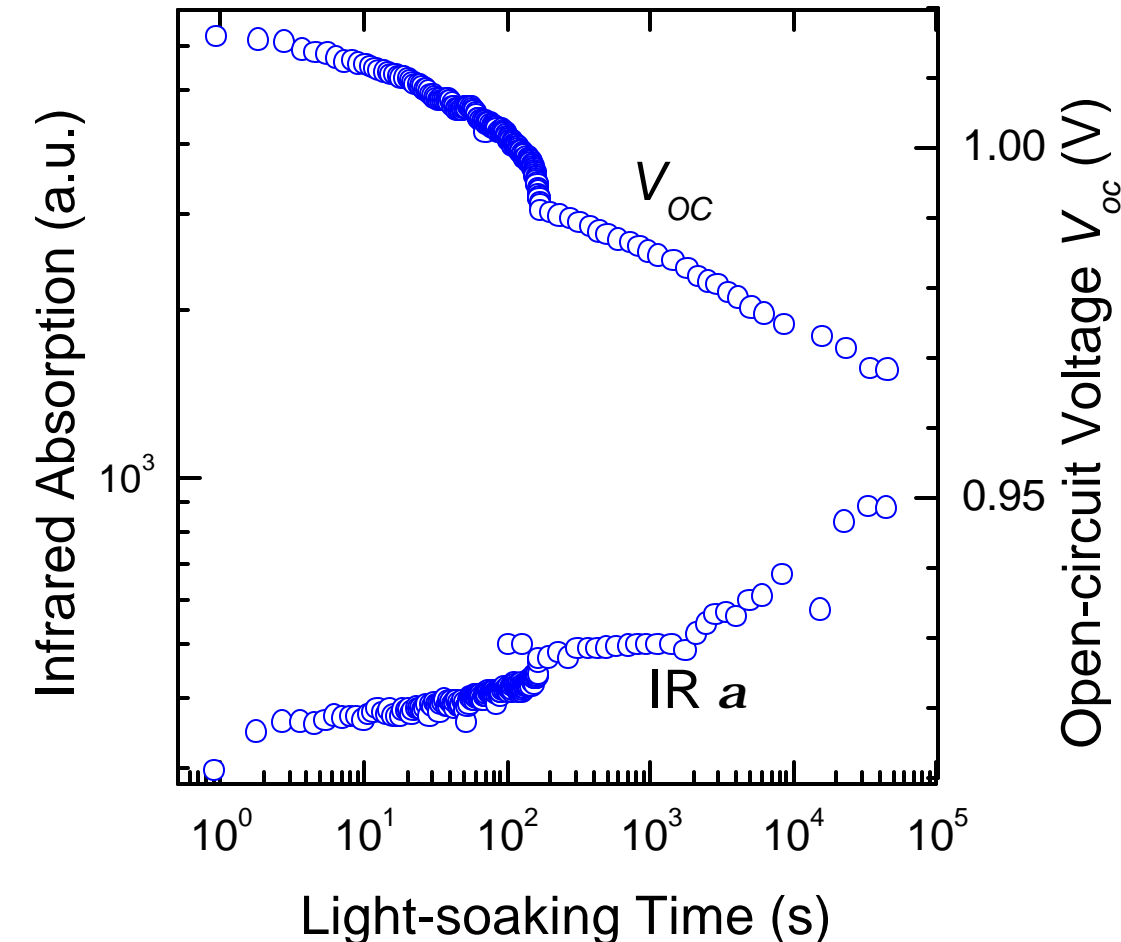
- Band & bandtail parameters for a-Si solar cell models
  - Low mobility of holes is probably a significant limitation (yesterday)
  - Measurements of  $V_{oc}$  vs.  $T$ , light-soaking (to complete parameter set)
  - Measurements of hole drift mobility (time-of-flight)
    - » What affects the hole mobility? We don't know.
    - » Fun with BP, PSU, USSC!
- Hole mobility estimates for  $\mu$ c-Si
  - Succeeding (collaboration w. Juelich)
  - Hole drift mobility around  $1 \text{ cm}^2/\text{Vs}$  at 300 K. Physics a puzzle.
- Infrared absorption spectroscopy of interfaces
  - Interesting, complicated spectra.
  - Not well explained by simple models for n/i and p/i interfaces. Looking at complexing & multi-phase models for doping.

# First Measurement: Infrared Absorption Spectrum of $p/i$ Interface in a-Si $pin$ Solar Cells



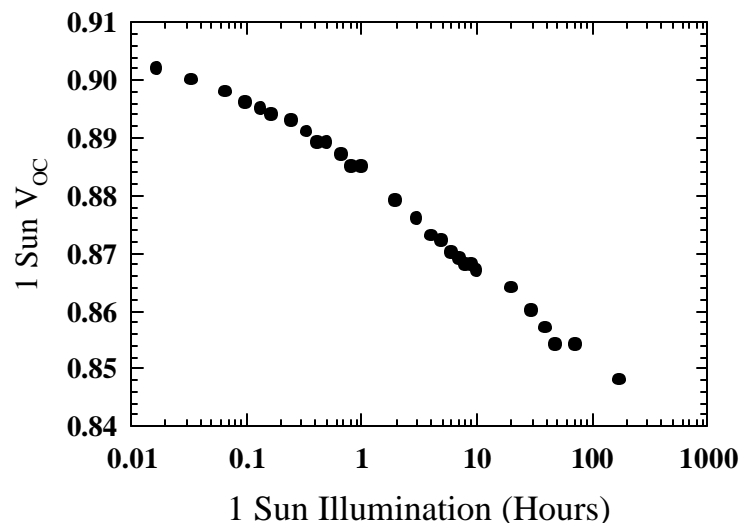
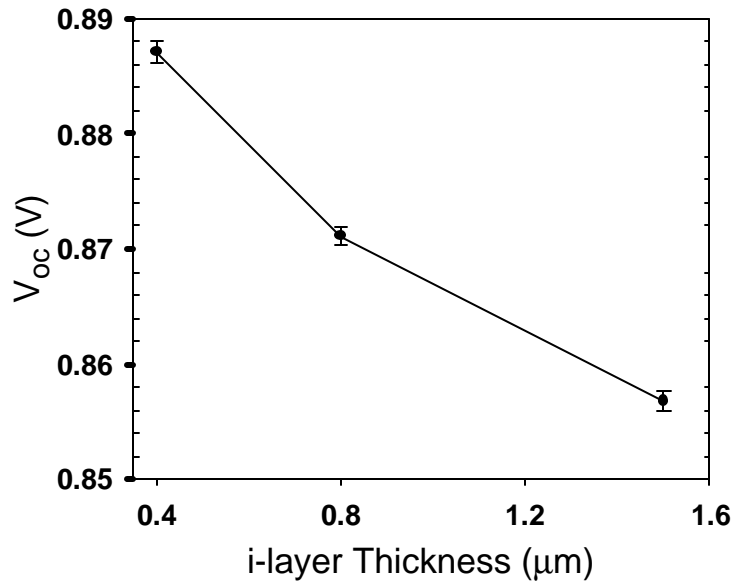
- Varying a-SiC:B p-layer sample series from BP Solar (thanks!)
- Charge modulation spectra show effect of varying B in p-layer.
  - Our goal!
- $E_F$  shift is a partial explanation, but more structure than expected.
  - $n$ -layers also full of surprises – which were likely evidence for complexing.

# A $V_{OC}$ & Metastability Oddity



- Goal of experiment was to determine  $V_{OC}$  when  $N_D = 0$  (by extrapolation).
- USSC solar cell (thanks)
- Used 1 s illumination “pulses” up to 100 s. Longer times, higher duty cycle after.
- Unexplained “kink” when duty-cycle changed. Seen twice.

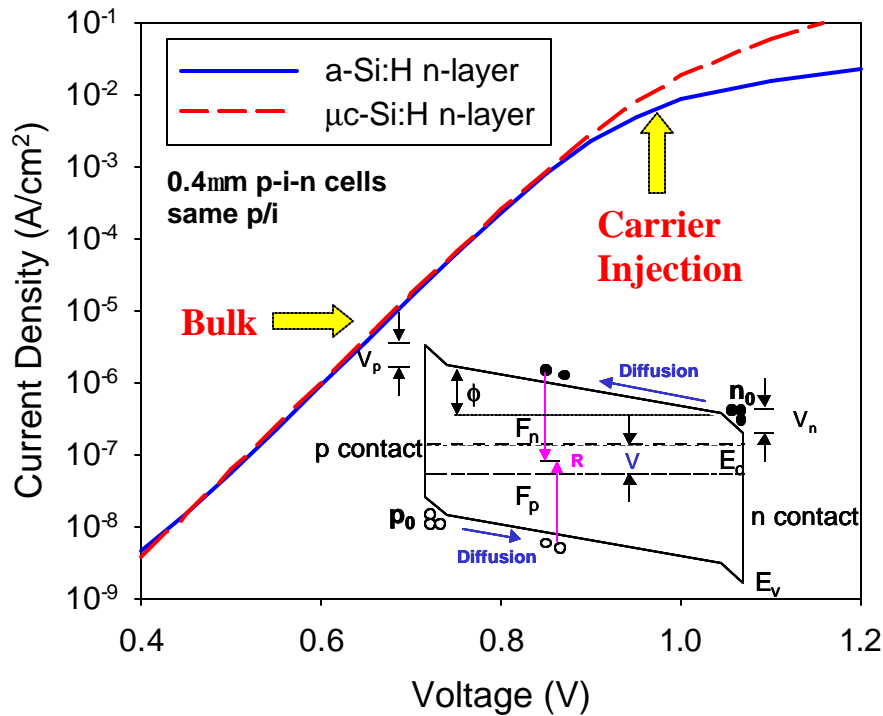




- Voltage regime over which bulk recombination dominates – limited by interface recombination.
- With optimized p/i, n/i interfaces – such transport can extend to 1 sun  $V_{OC}$ .
- On cells with i-layers having mobility gaps of 1.86 eV 1 sun  $V_{OC}$  values limited by bulk recombination have been identified.
- Systematic increases in bulk recombination in  $J_D$ - $V$  characteristics with i-layer thickness directly related to  $V_{OC}$  for  $J_{SC}$  of 7.5 mA/cm<sup>2</sup> with red light illumination.

## Light induced changes in $V_{OC}$ due to SWE in bulk:

- Confirm limitations imposed by recombination in the i-layers.
- Indicate absence of limitation due to recombination through tail states – whose densities are not affected by SWE.

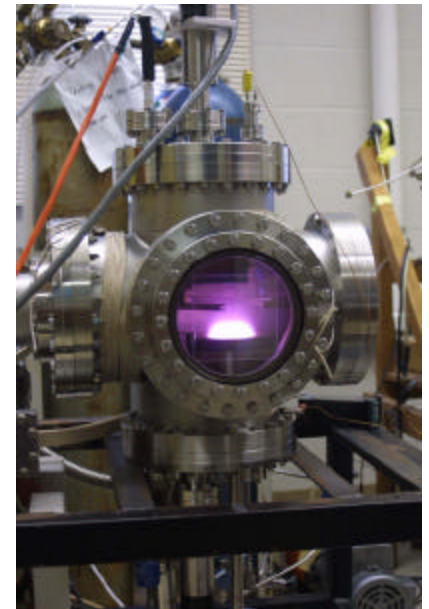


- $V_n$ : potential barrier in i-layer at n contact
- $V_n$  determined by space charge of electron filled gap states due to large  $n_0$  – not large densities of states.
- $n_0$  depends on alignment of  $E_F$  in n layer with  $E_c$  in i-layer.
- Alignment different for p-i-n cells with a-Si:H and  $\mu c$ -Si:H n contacts .
- Bulk recombination same.
- Carrier injection clearly lower for n-a-Si:H – higher  $V_n$ .
- **Consistent with**: close alignments of  $E_c$ , between i and n a-Si:H ( $E_A \sim 0.26eV$ ); 1.1eV bandgap of  $\mu c$ -Si:H,  $\sim$  equal discontinuities in  $E_c$  and  $E_v$  with i a-Si:H ( $E_A \sim 30meV$ ). (Koval et al., *J. Non. Cryst. Solids*, **299-302**, 1136, 2002)
- **Opposite** conclusion by Poissant et al. (*J. Appl. Phys.* **93**, 170, 2003) based purely on  $V_{OC}$  and modeling results.
- No effect on  $V_{OC}$  – zero current flow.

# Device Design and Efficiency Research

## *University of Toledo*

- To study the effect of interface layers at ITO-p and n-ZnO. Need to deposit 12 layers of triple cell without vacuum break
- A new self-designed 5-chamber system (four sputter + one loading) to allow uniform deposition of 4"x4" films (Ag, Al, ZnO, ITO) is being integrated into UT's existing 4-chamber PECVD/HWCVD system. Project 70% completed.
- One sputter chamber is completed. Uniform deposition achieved using a rotating substrate holder over a 3" sputter target. ITO film is being optimized in this chamber.



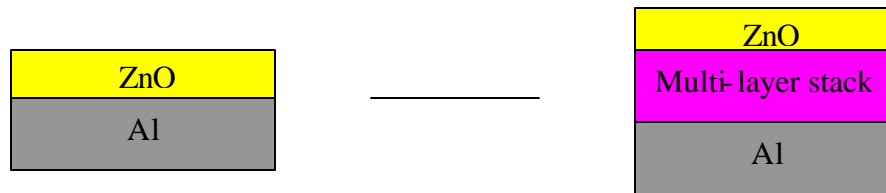
## Improved back reflectors using multi-layer approach

Energy Conversion Devices, Inc.

Greg Demaggio, Scott J. Jones (P.I.) Tongyu Liu, Jeff Steel and  
David Tsu

Goal: Devise new multi-layered back reflector that will lead to enhanced cell currents and improved efficiencies.

First Approach: Take present Al/ZnO back reflector used in production and add optical stack of materials with different indices for refraction. In particular, **add layers with high n to enhance reflection in the >600nm region.**



### Activities:

Focusing on multi-layer structure of (low n)/(high n)/(low n) materials

With **high n** material being **Si** and **low n** material being **ZnO** alloyed with elements identified as X and Y

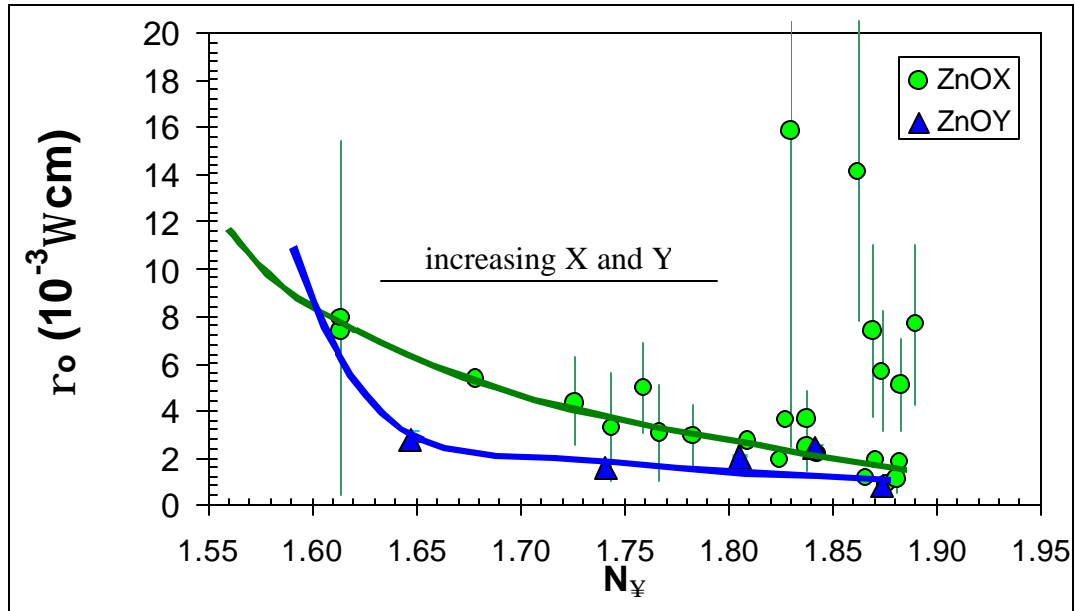


Using dc sputtering to fabricate layers

Most of our work has been on producing the ZnO alloys to prepare materials with:

- 1) High transparency
- 2) High conductivity
- 3) Low n (below 1.7)

Through alloying with X and Y, have been able to prepare materials with high conductivity ( $\rho_o < 10^{-3} \Omega\text{cm}$ ), high transparency (96-97%) and n between 1.6 and 1.7.



Initial Cell Performance **without optimization of layer thicknesses** demonstrates similar  $V_{oc}$ , FF and  $R_s$  for cells with Ag/ZnO and new back reflector materials – Currents need to be improved with proper optimization of back reflector film thicknesses.

Back reflector	$V_{oc}$ (V)	$J_{sc}$ ( $\text{mA}/\text{cm}^2$ )	FF	$R_s$ ( $\Omega \text{ cm}$ )	$P_{max}$ ( $\text{mW}/\text{cm}^2$ )
Ag/ZnO	0.641	22.68	0.497	8.7	7.23
Al with ZnOX	0.638	19.18	0.496	9.9	6.06
Al with ZnOY	0.639	20.60	0.494	9.6	6.50

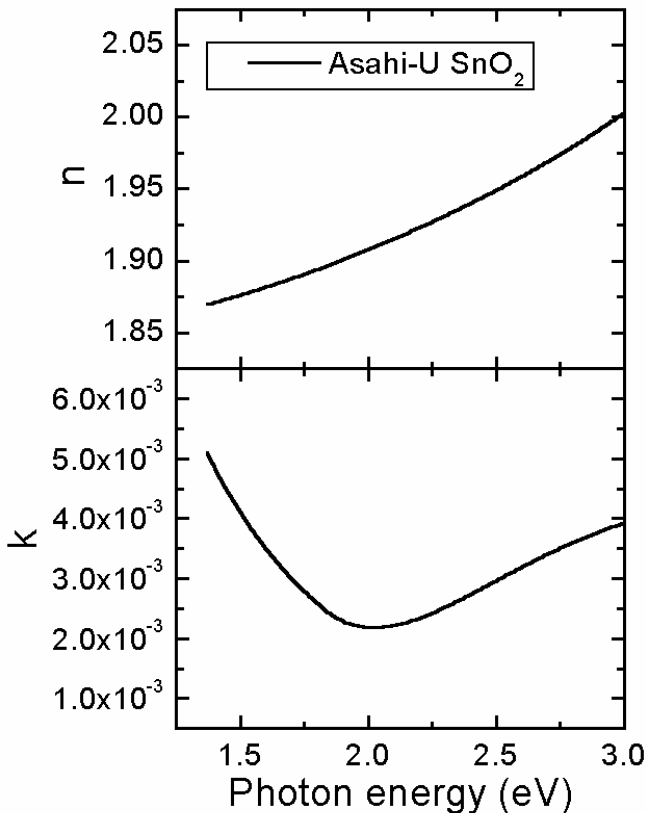


# DEVICE DESIGN AND EFFICIENCY

## OPTICALLY-BASED LIMITATIONS TO EFFICIENCY

**Goal:** A basic understanding of the optical physics of solar cells, verified through experimentation, that allows separation, quantification, and ultimately -- though simulation -- prediction of the optically-based limitations to solar cell efficiency

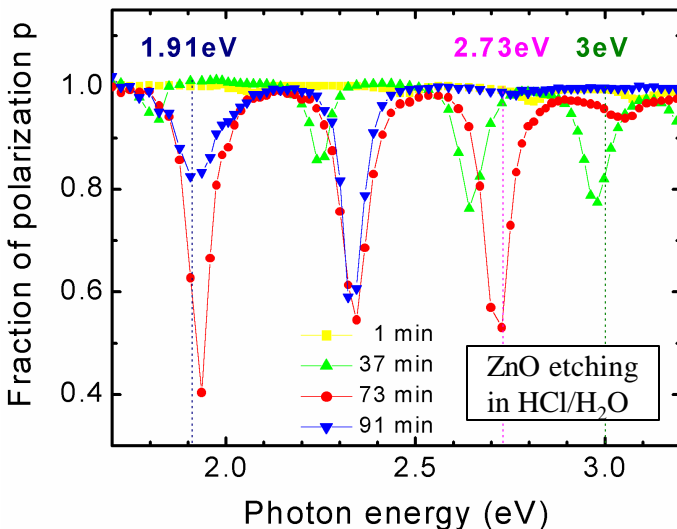
**New results: Advanced TCO measurement capabilities.**



Determination of optical properties and structure of materials in the textured state through\*:

- (i) better suppression of scattering via two-layer sandwich contacted with index-matching fluid
- (ii) improved separation of the absorption due to TCO and glass
- (iii) more advanced optical modeling that combines SE on textured surface (for  $n$ ) and T on index-matched sandwich (for  $k$ )

\* G. M. Ferreira et al., MRS Proc. (2003, in press)



Real time characterization of optical properties and *structural evolution* by "Mueller matrix ellipsometry"\*:

- (i) "microscopic scale" roughness from polarization change upon reflection
- (ii) "macroscopic scale" roughness from reflectance deficit
- (iii) "geometric scale" roughness from the degree of polarization

\* C. Chen, et al., Phys. Rev. Lett. **90**, 217402 (2003).



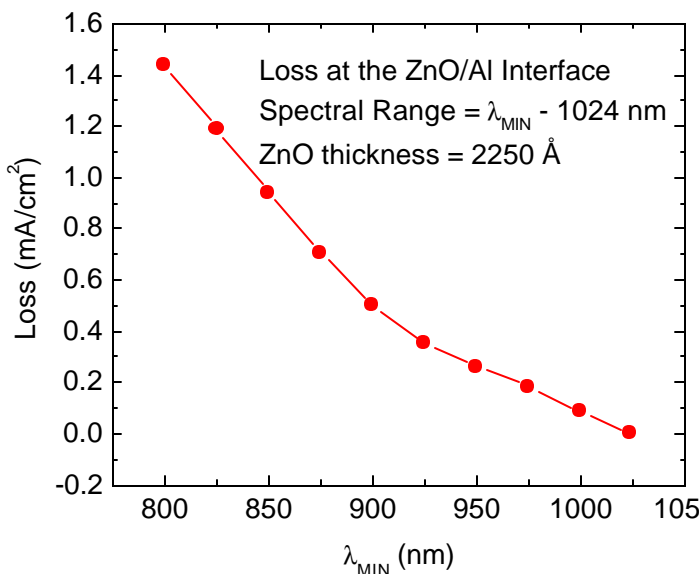
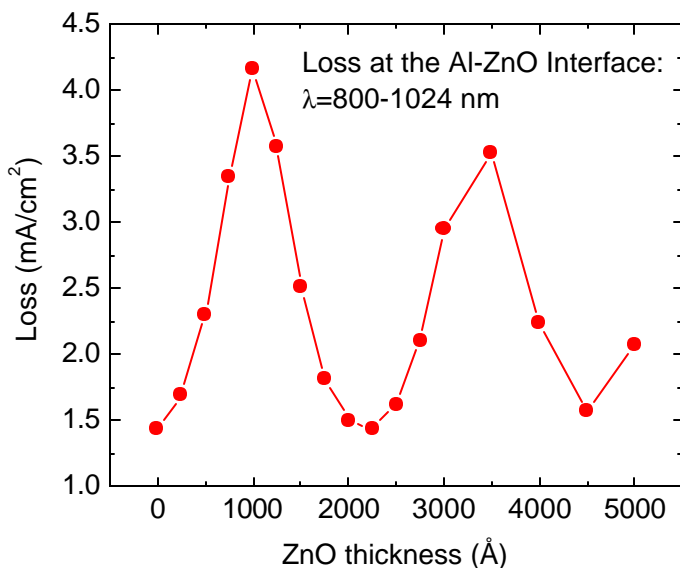
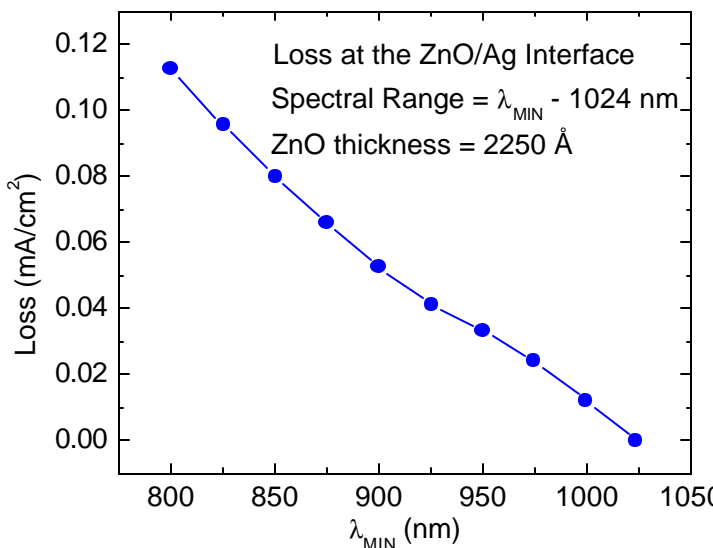
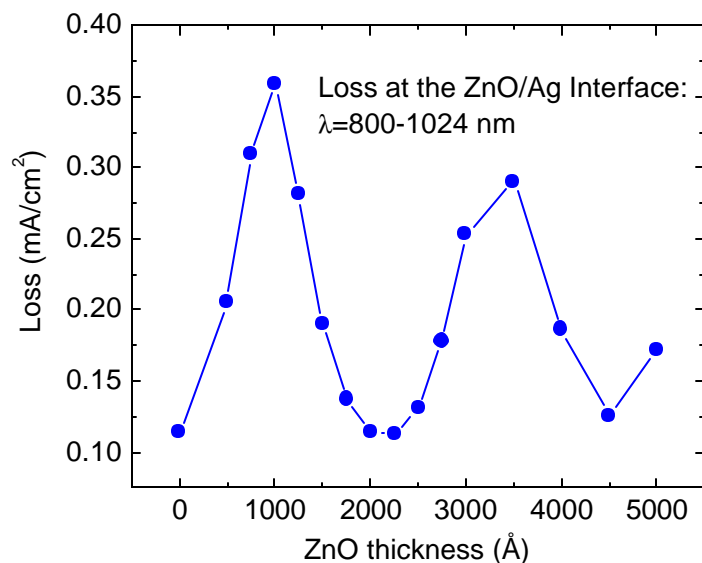
# DEVICE DESIGN AND EFFICIENCY

## OPTICALLY-BASED LIMITATIONS TO EFFICIENCY

**Goal:** Multilayer transparent conductors to minimize high energy reflection and parasitic absorption losses

**Approach:** Need a multilayer broad-band anti-reflector (400 - 800 nm) as a top contact; also need a multilayer broad band "perfect" reflector (800 - 1000 nm) as dielectric spacer in retroreflector

**Example of losses that must be overcome with this approach;  $DJ_{sc}$  obtained by integrating the absorption loss over the range from  $\lambda_{min} = 800 \text{ nm}$  to  $\lambda_{max} = 1024 \text{ nm}$**



# Device Design and Efficiency subteam **Team priorities**

## **Urgent Issues with highest priority**

- Fabricate and improve a-Si/a-SiGe/ $\mu$ c-Si triple cell **(USSC, UT)**
- Establish device physics related to  $\mu$ c-Si and thin film Si **(SU)**
- Study the dependence of  $\mu$ c-Si formation on different substrates **(UT)**
- Evaluate and improve the doped layer in multiple junction structure for  $\mu$ c-Si bottom cell i-layer **(USSC)**
- Study and control the p-i and n-i interface layers for narrow bandgap cells **(USSC, UT)**
- Deposition of a-SiGe and  $\mu$ c-Si material at high deposition rate **(USSC, ECD, UT, PSU)**
- Optical designs for light enhancement **(ECD, UT, PSU)**
- Identify and develop consensus on approaches that have the highest possibility to lead to 15% stable solar cells. **(USSC)**

## **Important Issues:**

- Characterization techniques for  $\mu$ c-Si and correlation of these measurements with device performance **(SU, UT)**
- Post-deposition treatment for  $\mu$ c-Si solar cells
- Understanding and improving Voc **(USSC, SU)**
- Deposition of  $\mu$ c-Si in large area. **(USSC)**



# Future Plans

## United Solar:

- Continue to optimize  $\mu\text{c-Si}$  materials and cells to be integrated into a-Si/a-SiGe/ $\mu\text{c-Si}$  triple-junction structure. a-Si top and a-SiGe will also be optimized
- Continue to optimize large area a-Si/a-SiGe/a-SiGe structure using constraints imposed by production conditions.

## ECD:

- Develop optically enhanced back reflector
- Develop high rate  $\mu\text{c-Si}$  deposition process

# Future Plans—Con'd

## Syracuse:

- Conduct hole mobility measurement for dilution series, deplete series, CIS
- Polymer/Si heterojunctions
- IR spectroscopy (interfaces,  $\mu\text{c-Si}$ )
- Device physics and modeling  $\rightarrow$  degraded state

## PSU—Wronski:

- Continue research in present areas.

# Future Plans—Con'd

## Collins (PSU and UT):

- Optimization of optical collection—expt.
  - Grading schemes in SiGe:H (UT)
  - Texturing of back-reflector ZnO (PSU)
  - Index variation in ITO and ZnO (UT)
  - Improved ZnO/metal interfaces
- Optimization of Optical Collection—Theory
  - Optical function of material components
  - Properties of interfaces
  - Micro/macro/geo roughness

# Future Plans—Con'd

## Collins (PSU and UT):

- Materials—Phase diagrams and protocrystalline SiGe:H
  - RF and VHF PECVD with SiH<sub>4</sub>/GeH<sub>4</sub> (PSU)
  - RF and VHF PECVD with Si<sub>2</sub>H<sub>6</sub>/GeH<sub>4</sub> (UT)
- Materials—Phase diagrams and optimization of uc-Si:H
  - RF, VHF, HWCVD (UT)

## Deng (UT)

- Deposit complete ITO/a-Si/a-SiGe/a-SiGe/Al/ZnO in an integrated system without vacuum break
- Deposit  $\mu$ c-Si solar cells using VHF PECVD and HWCVD